

**Search Notes**

Application/Control No.

10/698,325

Examiner

Hai C. Pham

Applicant(s)/Patent under  
Reexamination

REIHL, HEINER

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	236-237, 246-247	7/23/2005	HP
399	44, 47-51	7/23/2005	HP
	94-96		
	127-128		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/23/2005	HP